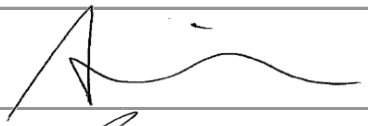
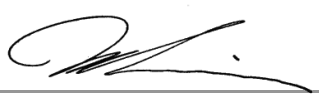
Headquarter Address:
8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
Shen Keng Dist, New Taipei City, Taiwan
TEL: +886-2-26620988
FAX: +886-2-26620488

Product/Process Change Notification

PCN#	Effective Date	Issue Date
2021-09-16C-01	2021/10/16	2021/9/16
PCN Classification	Product Category	
Minor	Mosfet	
Subject		
Specification change		
Affected Product(s)		
SSG4835P-C		
Description of Change(s)		
In order to improve production efficiency and product yield, we relax product specifications. No change in wafer and assembly.		
Content of Change(s)		
Specification		
Impact(s)		
N/A		
Attachment(s)		
Specification		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

www.SeCosGmbH.com

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Specification Electrical Comparison Chart

Symbol	original spe	new spe	Unit
VDS	-30	-30	V
IGSS	±100	±100	nA
IDSS	-1	-1	uA
VGS(th)	>-1	-1~-2.5	V
Rdson(@ -10V)	19	21	mΩ
Rdson(@ -4.5V)	30	32	mΩ
VSD	-0.7 (typ)	-1.2 (Max)	V
Qg	15.3	12.6	nC
Qgs	5.2	4.8	nC
Qgd	5.8	4.8	nC
Td(on)	15	4.6	nS
Tr	12	14.8	nS
Td(off)	62	41	nS
Tf	46	19.6	nS

Elektronische Bauelemente

SSG4835P-C

-8A, -30V, $R_{DS(ON)}$ 21mΩ
P-Ch Enhancement Mode Power MOSFET

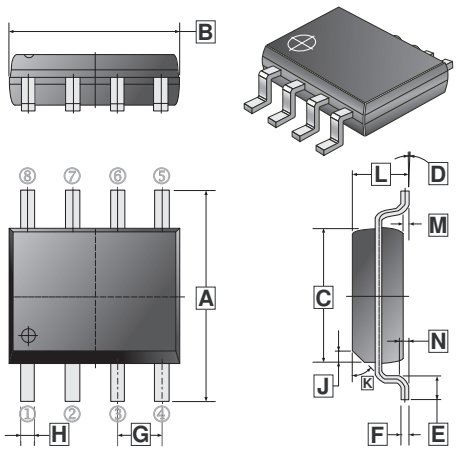
RoHS Compliant Product
A suffix of "-C" specifies halogen & lead-free

DESCRIPTION

The SSG4835P-C is the highest performance trench P-ch MOSFETs with extreme high cell density, which provide excellent $R_{DS(ON)}$ and gate charge for most of the synchronous buck converter applications .

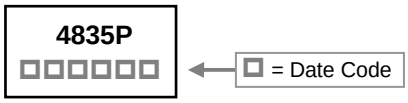
The SSG4835P-C meet the RoHS and Green Product requirement with full function reliability approved.

SOP-8



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.79	6.20	H	0.33	0.51
B	4.70	5.11	J	0.375 REF.	
C	3.80	4.00	K	45°REF.	
D	0°	8°	L	1.3	1.752
E	0.40	1.27	M	0	0.25
F	0.10	0.25	N	0.25 REF.	
G	1.27 TYP.				

MARKING

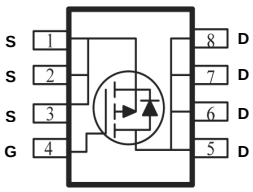


PACKAGE INFORMATION

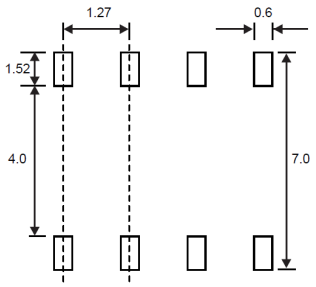
Package	MPQ	Leader Size
SOP-8	2.5K	13 inch

ORDER INFORMATION

Part Number	Type
SSG4835P-C	Lead (Pb)-free and Halogen-free



Mounting Pad Layout



*Dimensions in millimeters

MAXIMUM RATINGS

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DS}	-30	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current @V_{GS}=10V [1]	T_A=25℃	I_D	-8	A
	T_A=70℃		-6	A
Pulsed Drain Current [3]		I_{DM}	-50	A
Total Power Dissipation	T_A=25℃	P_D	1.5	W
Operating Junction & Storage Temperature Range		T_J, T_{STG}	-55 ~ 150	℃
Thermal Resistance Ratings				
Thermal Resistance Junction-Ambient [1] (Max.)		$R_{\theta JA}$	85	℃/W
Thermal Resistance Junction-Ambient [2]			125	
Thermal Resistance Junction-Case [1] (Max.)		$R_{\theta JC}$	36	

ELECTRICAL CHARACTERISTICS (T_J=25°C unless otherwise specified)

Parameter		Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage		BV_{DSS}	-30	-	-	V	V_{GS}=0, I_D= -250uA
Gate Threshold Voltage		$V_{GS(th)}$	-1	-	-2.5	V	V_{DS}=V_{GS}, I_D= -250μA
Gate-Body Leakage		I_{GSS}	-	-	±100	nA	V_{DS}= 0V, V_{GS}= ±20V
Zero Gate Voltage Drain Current	T_J=25℃	I_{DSS}	-	-	-1	μA	V_{DS}= -24V, V_{GS}=0V
	T_J=55℃		-	-	-5		V_{DS}= -24V, V_{GS}=0V
Drain-Source On-Resistance [4]		$R_{DS(ON)}$	-	-	21	mΩ	V_{GS}= -10V, I_D= -6A
			-	-	32		V_{GS}= -4.5V, I_D= -4A
Gate Resistance		R_g	-	15	-	Ω	f=1MHz
Forward Transconductance		g_{fs}	-	17	-	S	V_{DS}= -5V, I_D= -6A
Total Gate Charge		Q_g	-	12.6	-	nC	I_D= -6A V_{DS}= -15V V_{GS}= -4.5V
Gate-Source Charge		Q_{gs}	-	4.8	-		
Gate-Drain Charge		Q_{gd}	-	4.8	-		
Turn-On Delay Time		$T_{d(on)}$	-	4.6	-	nS	V_{DD}= -15V I_D= -6A V_{GS}= -10V R_G=3.3Ω
Rise Time		T_r	-	14.8	-		
Turn-Off Delay Time		$T_{d(off)}$	-	41	-		
Fall Time		T_f	-	19.6	-		
Input Capacitance		C_{iss}	-	1345	-	pF	V_{DS}= -15V V_{GS}=0 f=1MHz
Output Capacitance		C_{oss}	-	194	-		
Reverse Transfer Capacitance		C_{rss}	-	158	-		
Source-Drain Diode							
Continuous Source Current [1]		I_S	-	-	-8	A	
Pulsed Source Current [3]		I_{SM}	-	-	-50	A	
Diode Forward Voltage [4]		V_{SD}	-	-	-1.2	V	V_{GS}=0V, I_S= -1A, T_J=25℃
Reverse Recovery Time		t_{rr}	-	16.3	-	nS	I_F= -6A, dI/dt=100A/μs, T_J=25℃
Reverse Recovery Charge		Q_{rr}	-	5.9	-	nC	

Notes:
1. Surface mounted on a 1 inch^2 FR-4 board with 2oz copper.
2. When mounted on Min. copper pad.
3. Pulse width limited by maximum junction temperature, Pulse Width≤300μs, Duty Cycle≤2%
4. The data tested by pulsed, pulse width≤300us, duty cycle≤2%

CHARACTERISTIC CURVES

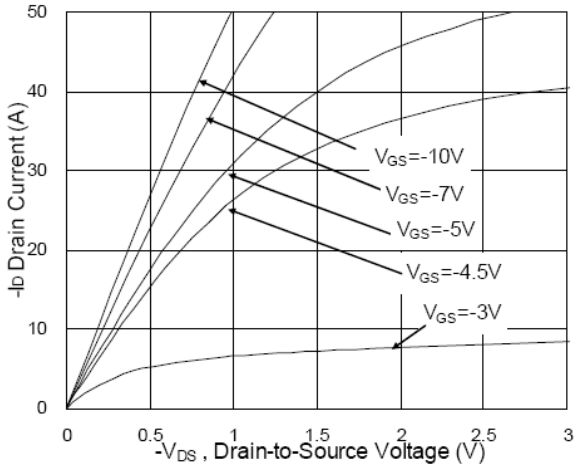


Fig.1 Typical Output Characteristics

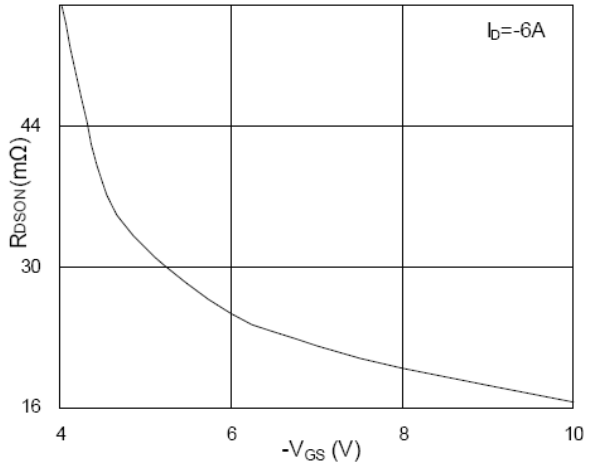


Fig.2 On-Resistance v.s Gate-Source

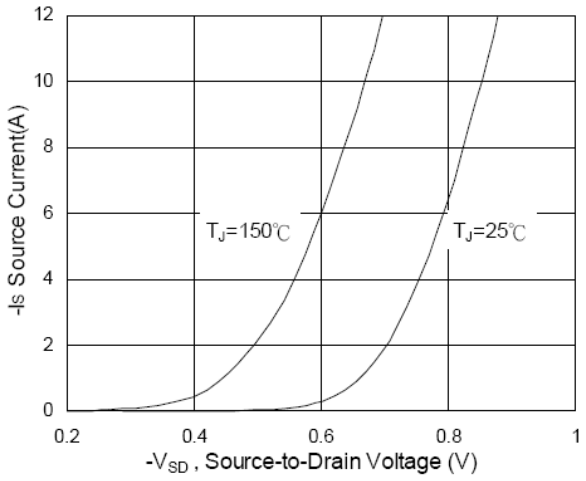


Fig.3 Forward Characteristics of Reverse

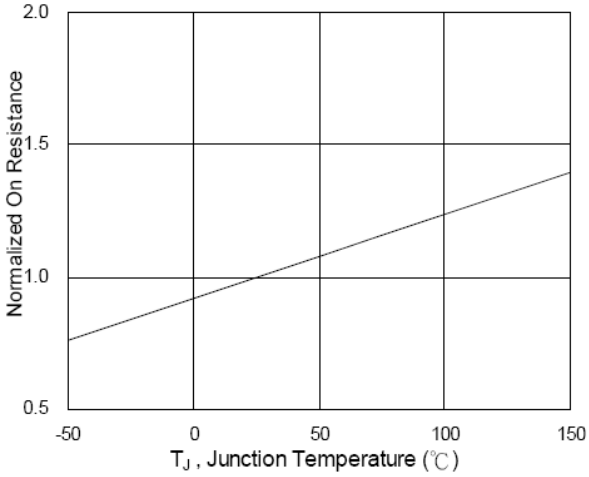


Fig.6 Normalized R_{DSON} vs. T_J

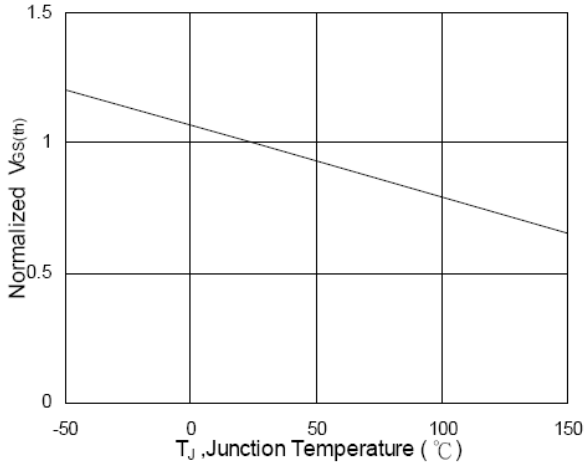


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

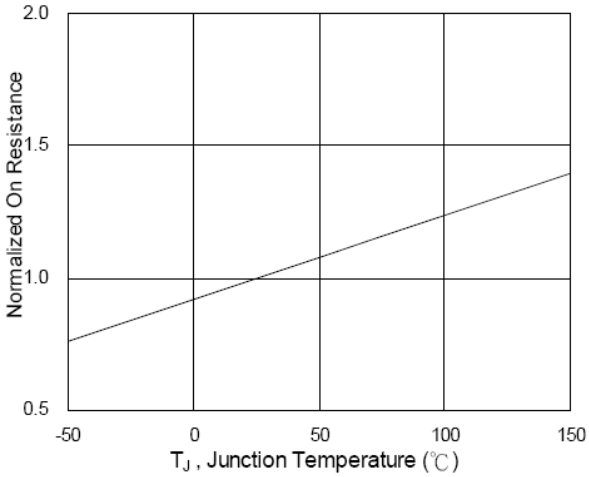


Fig.6 Normalized R_{DSON} vs. T_J

CHARACTERISTIC CURVES

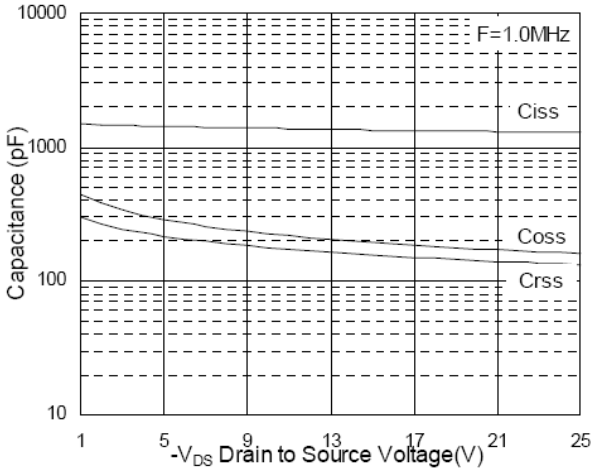


Fig.7 Capacitance

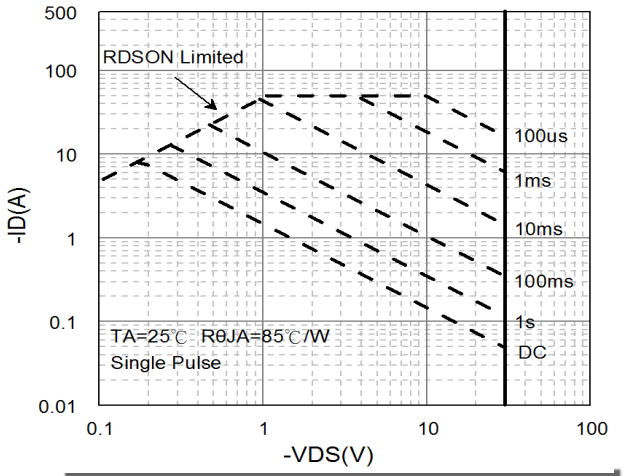


Fig.8 Safe Operating Area

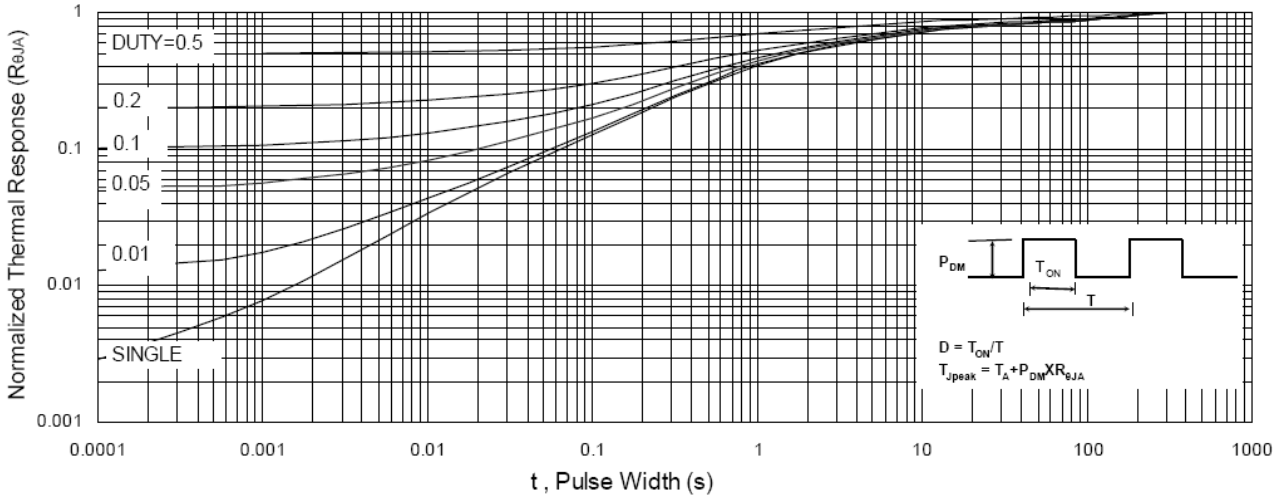


Fig.9 Normalized Maximum Transient Thermal Impedance

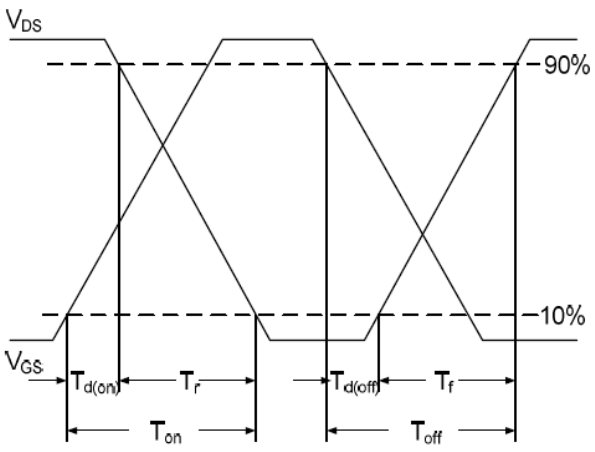


Fig.10 Switching Time Waveform

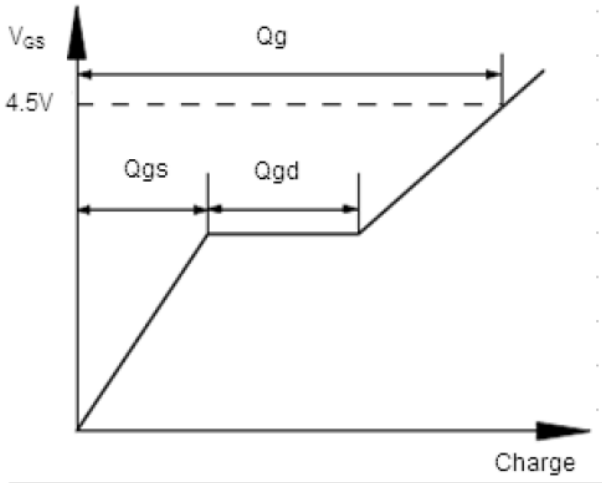


Fig.11 Gate Charge Waveform

SeCoS Corporation

Reliability Testing Summary Report

Date: 2021/09/10 Document No.: SO21 -09-SG4835P

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SSG4835P-C	150 ± 5℃, 80%VR, T = 1000 Hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SSG4835P-C	150℃, T = 1000 Hrs		77	0	0	ACC
PCT Pressure Cooker Test	SSG4835P-C	121℃, 29.7PSIG, 168 Hrs		77	0	0	ACC
TCT Temperature Cycle Test	SSG4835P-C	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SSG4835P-C	85 ± 2℃, RH=85±5%, 1000 Hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SSG4835P-C	85 ± 2℃, RH=85±5%, 80%VR, 1000 Hrs		77	0	0	ACC
Solderability	SSG4835P-C	245 ± 5℃, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2021.07.12 Testing End Date: 2021.09.10

Tester: King Huang Approval: Peter Yang

SeCoS Corporation

Electrical Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 25℃
Test Date: 2021.07.12
Test Standard : Specifications
Operator: Joe Lee

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-40.17V	-6.627nA	19.88mΩ
2	-43.31V	-6.571nA	19.57mΩ
3	-41.93V	-6.638nA	19.53mΩ
4	-40.80V	-6.805nA	19.40mΩ
5	-41.65V	-6.616nA	19.33mΩ
6	-43.70V	-6.874nA	19.90mΩ
7	-43.54V	-6.547nA	19.75mΩ
8	-41.69V	-7.089nA	19.62mΩ
9	-41.56V	-7.417nA	19.76mΩ
10	-41.57V	-7.625nA	19.97mΩ
11	-40.05V	-7.242nA	20.31mΩ
12	-42.29V	-7.049nA	19.38mΩ
13	-42.26V	-7.571nA	19.27mΩ
14	-41.19V	-7.175nA	20.12mΩ
15	-40.10V	-6.923nA	19.46mΩ
16	-41.24V	-7.531nA	19.52mΩ
17	-42.80V	-7.421nA	20.05mΩ
18	-41.81V	-6.870nA	19.45mΩ
19	-41.12V	-7.187nA	19.86mΩ
20	-41.63V	-6.818nA	19.40mΩ
21	-42.75V	-6.927nA	19.65mΩ
22	-39.41V	-6.501nA	19.47mΩ
23	-42.24V	-6.997nA	19.62mΩ
24	-41.92V	-7.402nA	19.62mΩ
25	-39.95V	-6.974nA	20.28mΩ
26	-43.52V	-6.618nA	19.96mΩ
27	-43.73V	-6.731nA	19.75mΩ
28	-40.55V	-7.408nA	19.47mΩ
29	-43.23V	-7.179nA	19.68mΩ
30	-42.17V	-6.787nA	19.29mΩ

SeCoS Corporation

Electrical Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 25℃
Test Date: 2021.07.12
Test Standard : Specifications
Operator: Joe Lee

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
31	-40.64V	-7.120nA	20.05mΩ
32	-41.80V	-7.204nA	20.18mΩ
33	-43.48V	-6.576nA	19.91mΩ
34	-41.15V	-6.707nA	19.95mΩ
35	-41.05V	-7.152nA	19.33mΩ
36	-40.11V	-7.163nA	19.49mΩ
37	-41.19V	-7.342nA	19.51mΩ
38	-43.23V	-6.658nA	19.95mΩ
39	-41.60V	-7.313nA	20.05mΩ
40	-39.39V	-6.671nA	19.80mΩ
41	-42.21V	-6.928nA	19.85mΩ
42	-42.75V	-6.744nA	20.37mΩ
43	-39.70V	-6.830nA	19.90mΩ
44	-40.61V	-7.206nA	19.27mΩ
45	-41.83V	-6.771nA	20.29mΩ
46	-40.64V	-7.212nA	20.22mΩ
47	-42.51V	-6.891nA	19.92mΩ
48	-42.42V	-7.622nA	20.04mΩ
49	-39.50V	-6.895nA	20.37mΩ
50	-40.85V	-6.869nA	20.16mΩ
51	-41.21V	-7.349nA	19.95mΩ
52	-40.20V	-6.685nA	19.84mΩ
53	-40.11V	-7.609nA	20.25mΩ
54	-43.01V	-7.418nA	19.43mΩ
55	-41.99V	-7.151nA	20.39mΩ
56	-41.54V	-7.107nA	19.71mΩ
57	-42.43V	-6.827nA	19.43mΩ
58	-41.59V	-6.832nA	19.98mΩ
59	-41.69V	-7.452nA	19.92mΩ
60	-41.11V	-7.507nA	19.85mΩ

SeCoS Corporation

Electrical Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 25℃
Test Date: 2021.07.12
Test Standard : Specifications
Operator: Joe Lee

Test Result: PASS

No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
61	-39.37V	-7.053nA	20.03mΩ
62	-43.36V	-6.811nA	19.28mΩ
63	-40.46V	-7.537nA	20.16mΩ
64	-40.23V	-6.929nA	20.12mΩ
65	-43.68V	-6.613nA	19.61mΩ
66	-40.97V	-7.049nA	20.10mΩ
67	-39.78V	-7.334nA	19.59mΩ
68	-40.65V	-6.796nA	20.30mΩ
69	-43.71V	-6.989nA	20.28mΩ
70	-40.77V	-6.558nA	19.28mΩ
71	-43.61V	-6.661nA	19.97mΩ
72	-40.92V	-6.836nA	19.72mΩ
73	-40.50V	-6.657nA	19.78mΩ
74	-40.93V	-7.238nA	19.72mΩ
75	-40.92V	-7.540nA	19.57mΩ
76	-41.57V	-7.483nA	19.74mΩ
77	-39.54V	-6.760nA	19.56mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 150 ± 5℃, 80%VR, T = 1000 Hrs
Test Date: 2021.07.13 ~ 2020.08.25
Test Standard : JESD22 STANDARD Method-A108
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-39.92V	-7.658nA	19.51mΩ	-41.81V	-6.866nA	19.39mΩ
2	-41.70V	-6.619nA	19.59mΩ	-43.43V	-7.297nA	20.30mΩ
3	-39.61V	-7.655nA	19.95mΩ	-40.63V	-6.880nA	19.48mΩ
4	-40.47V	-6.764nA	19.55mΩ	-43.16V	-7.276nA	20.17mΩ
5	-39.38V	-6.817nA	20.08mΩ	-42.11V	-7.338nA	20.08mΩ
6	-41.07V	-7.603nA	20.20mΩ	-40.77V	-6.632nA	20.15mΩ
7	-40.83V	-7.197nA	19.38mΩ	-42.43V	-6.509nA	19.94mΩ
8	-39.66V	-7.307nA	20.12mΩ	-43.60V	-7.460nA	20.18mΩ
9	-41.95V	-6.671nA	19.82mΩ	-40.28V	-7.644nA	19.32mΩ
10	-39.89V	-6.622nA	19.67mΩ	-39.40V	-7.022nA	19.62mΩ
11	-41.98V	-7.412nA	20.14mΩ	-43.07V	-6.691nA	20.26mΩ
12	-39.63V	-7.574nA	20.16mΩ	-40.29V	-7.253nA	19.64mΩ
13	-42.21V	-7.433nA	19.94mΩ	-43.13V	-6.775nA	19.57mΩ
14	-40.72V	-6.957nA	19.82mΩ	-39.41V	-6.554nA	19.63mΩ
15	-39.93V	-6.530nA	19.57mΩ	-41.21V	-6.815nA	19.33mΩ
16	-39.58V	-7.543nA	20.24mΩ	-42.03V	-7.531nA	20.33mΩ
17	-42.73V	-7.511nA	20.23mΩ	-43.00V	-7.591nA	19.97mΩ
18	-39.47V	-7.435nA	19.60mΩ	-43.04V	-7.239nA	19.88mΩ
19	-41.89V	-6.925nA	19.71mΩ	-42.10V	-6.826nA	20.08mΩ
20	-41.48V	-7.391nA	19.99mΩ	-40.08V	-6.823nA	19.65mΩ
21	-42.32V	-7.028nA	19.89mΩ	-43.44V	-7.065nA	20.29mΩ
22	-42.59V	-7.373nA	20.06mΩ	-42.11V	-7.146nA	19.46mΩ
23	-39.35V	-7.623nA	19.43mΩ	-39.78V	-6.513nA	19.38mΩ
24	-41.78V	-6.827nA	19.86mΩ	-41.39V	-7.283nA	20.32mΩ
25	-39.44V	-7.025nA	19.94mΩ	-40.43V	-6.718nA	19.65mΩ
26	-43.22V	-7.479nA	19.37mΩ	-40.01V	-7.100nA	20.21mΩ
27	-43.58V	-7.294nA	20.13mΩ	-39.61V	-6.542nA	20.15mΩ
28	-41.03V	-6.930nA	19.32mΩ	-42.09V	-7.114nA	19.96mΩ
29	-39.68V	-7.221nA	20.27mΩ	-43.42V	-7.073nA	20.11mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 150 ± 5℃, 80%VR, T = 1000 Hrs
Test Date: 2021.07.13 ~ 2020.08.25
Test Standard : JESD22 STANDARD Method-A108
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-40.05V	-6.545nA	20.02mΩ	-39.51V	-6.820nA	19.33mΩ
31	-39.44V	-7.339nA	20.09mΩ	-40.50V	-6.988nA	20.33mΩ
32	-39.88V	-6.693nA	19.35mΩ	-39.62V	-7.546nA	19.90mΩ
33	-43.60V	-6.675nA	19.27mΩ	-39.96V	-6.725nA	19.70mΩ
34	-42.83V	-7.449nA	19.34mΩ	-43.28V	-6.805nA	19.71mΩ
35	-43.16V	-7.582nA	20.18mΩ	-41.14V	-6.732nA	19.36mΩ
36	-43.04V	-6.552nA	19.81mΩ	-39.30V	-7.193nA	20.31mΩ
37	-39.63V	-7.469nA	19.52mΩ	-41.16V	-7.068nA	20.38mΩ
38	-42.22V	-6.576nA	19.71mΩ	-40.18V	-6.699nA	20.20mΩ
39	-43.26V	-7.605nA	20.38mΩ	-39.84V	-6.801nA	20.37mΩ
40	-43.43V	-6.584nA	19.97mΩ	-41.77V	-6.855nA	20.24mΩ
41	-39.52V	-7.434nA	19.31mΩ	-41.15V	-6.584nA	19.45mΩ
42	-42.77V	-7.315nA	19.62mΩ	-40.56V	-7.391nA	19.94mΩ
43	-40.31V	-7.072nA	20.38mΩ	-43.71V	-7.186nA	20.17mΩ
44	-42.26V	-6.551nA	20.01mΩ	-41.45V	-7.371nA	20.40mΩ
45	-39.92V	-7.290nA	19.50mΩ	-40.81V	-6.701nA	20.13mΩ
46	-40.46V	-7.656nA	20.03mΩ	-41.30V	-7.263nA	19.99mΩ
47	-41.25V	-7.322nA	20.02mΩ	-39.49V	-6.647nA	19.71mΩ
48	-43.44V	-6.502nA	19.64mΩ	-40.14V	-7.425nA	19.92mΩ
49	-42.06V	-7.105nA	19.88mΩ	-40.46V	-6.711nA	20.14mΩ
50	-41.02V	-6.763nA	19.72mΩ	-40.16V	-7.039nA	19.98mΩ
51	-39.38V	-7.337nA	19.93mΩ	-42.88V	-7.203nA	20.09mΩ
52	-39.40V	-7.001nA	19.48mΩ	-40.50V	-7.142nA	19.87mΩ
53	-43.16V	-7.246nA	20.29mΩ	-42.27V	-7.198nA	19.33mΩ
54	-41.24V	-7.012nA	19.77mΩ	-43.58V	-7.444nA	19.81mΩ
55	-39.49V	-6.785nA	19.45mΩ	-43.65V	-6.578nA	20.08mΩ
56	-43.56V	-6.647nA	19.49mΩ	-42.91V	-7.281nA	19.76mΩ
57	-39.54V	-6.564nA	19.70mΩ	-43.40V	-7.096nA	19.79mΩ
58	-41.42V	-7.295nA	20.09mΩ	-43.10V	-7.585nA	19.71mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 150 ± 5℃, 80%VR, T = 1000 Hrs
Test Date: 2021.07.13 ~ 2020.08.25
Test Standard : JESD22 STANDARD Method-A108
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-43.28V	-7.221nA	19.37mΩ	-42.75V	-7.443nA	20.26mΩ
60	-42.39V	-6.771nA	19.51mΩ	-41.10V	-6.560nA	20.01mΩ
61	-39.84V	-7.522nA	20.40mΩ	-42.49V	-6.611nA	19.40mΩ
62	-42.21V	-6.659nA	19.93mΩ	-43.73V	-7.633nA	19.37mΩ
63	-43.06V	-6.788nA	20.31mΩ	-40.78V	-7.527nA	19.84mΩ
64	-42.87V	-6.956nA	20.36mΩ	-40.42V	-6.822nA	19.75mΩ
65	-40.05V	-7.227nA	19.39mΩ	-40.82V	-6.958nA	20.27mΩ
66	-42.40V	-6.570nA	19.34mΩ	-41.22V	-6.531nA	19.78mΩ
67	-40.80V	-6.575nA	19.75mΩ	-40.15V	-7.234nA	20.32mΩ
68	-40.35V	-6.615nA	19.98mΩ	-42.75V	-7.116nA	20.17mΩ
69	-42.75V	-7.119nA	19.35mΩ	-40.79V	-7.627nA	19.73mΩ
70	-42.59V	-7.261nA	20.40mΩ	-41.55V	-7.057nA	19.94mΩ
71	-40.94V	-6.823nA	19.35mΩ	-40.72V	-7.656nA	19.30mΩ
72	-41.53V	-7.493nA	20.18mΩ	-39.56V	-6.638nA	19.79mΩ
73	-39.54V	-7.184nA	19.34mΩ	-41.51V	-7.522nA	19.78mΩ
74	-39.66V	-6.704nA	20.34mΩ	-42.48V	-7.106nA	19.95mΩ
75	-39.90V	-7.226nA	20.12mΩ	-41.72V	-7.128nA	20.37mΩ
76	-39.94V	-7.180nA	20.16mΩ	-40.51V	-7.221nA	20.02mΩ
77	-41.77V	-7.587nA	20.05mΩ	-39.71V	-7.468nA	20.06mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 150℃, 1000Hrs
Test Date: 2021.07.13 ~ 2020.08.25
Test Standard : JESD22 STANDARD Method-A103
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-40.19V	-7.465nA	19.47mΩ	-43.20V	-7.035nA	20.38mΩ
2	-40.13V	-6.807nA	19.32mΩ	-42.40V	-6.857nA	19.79mΩ
3	-39.53V	-6.975nA	19.65mΩ	-42.92V	-7.659nA	20.30mΩ
4	-41.77V	-7.212nA	20.15mΩ	-39.87V	-7.511nA	19.69mΩ
5	-41.33V	-6.667nA	20.09mΩ	-41.79V	-7.489nA	19.67mΩ
6	-40.14V	-7.443nA	20.03mΩ	-43.47V	-6.962nA	20.07mΩ
7	-41.62V	-7.565nA	20.04mΩ	-43.02V	-6.596nA	19.97mΩ
8	-42.53V	-7.048nA	19.94mΩ	-41.02V	-7.205nA	19.55mΩ
9	-42.21V	-7.428nA	19.30mΩ	-41.97V	-6.854nA	20.23mΩ
10	-42.78V	-6.697nA	20.01mΩ	-42.27V	-7.129nA	19.98mΩ
11	-41.55V	-6.987nA	19.32mΩ	-40.90V	-6.781nA	19.92mΩ
12	-41.70V	-6.811nA	19.63mΩ	-39.64V	-7.030nA	19.71mΩ
13	-41.74V	-7.595nA	19.57mΩ	-42.28V	-7.489nA	19.75mΩ
14	-40.05V	-6.957nA	19.32mΩ	-42.76V	-7.094nA	19.52mΩ
15	-40.42V	-7.558nA	19.46mΩ	-39.94V	-7.018nA	20.26mΩ
16	-40.16V	-7.594nA	19.59mΩ	-40.19V	-6.503nA	19.96mΩ
17	-39.36V	-7.126nA	20.35mΩ	-39.88V	-6.646nA	19.61mΩ
18	-41.00V	-7.455nA	19.32mΩ	-41.62V	-6.617nA	19.75mΩ
19	-41.85V	-7.608nA	19.53mΩ	-42.06V	-7.317nA	20.14mΩ
20	-43.08V	-7.222nA	20.36mΩ	-40.90V	-7.121nA	20.35mΩ
21	-39.84V	-7.466nA	20.18mΩ	-42.16V	-7.353nA	19.72mΩ
22	-40.14V	-6.681nA	19.92mΩ	-41.93V	-6.709nA	19.86mΩ
23	-43.68V	-6.611nA	20.32mΩ	-41.96V	-7.462nA	20.35mΩ
24	-43.06V	-6.917nA	20.11mΩ	-42.29V	-6.503nA	19.45mΩ
25	-42.71V	-7.464nA	20.28mΩ	-42.76V	-6.720nA	20.34mΩ
26	-43.04V	-7.266nA	19.92mΩ	-39.69V	-7.499nA	19.82mΩ
27	-39.59V	-6.529nA	20.33mΩ	-43.11V	-7.149nA	20.37mΩ
28	-39.69V	-7.424nA	20.26mΩ	-43.72V	-6.656nA	19.33mΩ
29	-40.64V	-7.308nA	20.11mΩ	-39.98V	-7.553nA	20.00mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 150℃, 1000Hrs
Test Date: 2021.07.13 ~ 2020.08.25
Test Standard : JESD22 STANDARD Method-A103
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-39.57V	-7.561nA	19.25mΩ	-41.77V	-6.939nA	19.78mΩ
31	-40.96V	-6.776nA	20.19mΩ	-40.72V	-7.379nA	19.65mΩ
32	-42.40V	-6.697nA	19.48mΩ	-43.45V	-7.359nA	19.73mΩ
33	-39.81V	-6.534nA	19.93mΩ	-40.68V	-7.084nA	19.47mΩ
34	-43.57V	-7.128nA	19.46mΩ	-43.42V	-6.813nA	19.36mΩ
35	-43.04V	-6.566nA	19.35mΩ	-41.97V	-6.960nA	19.78mΩ
36	-39.90V	-7.153nA	20.20mΩ	-39.78V	-7.490nA	20.10mΩ
37	-41.63V	-6.890nA	20.07mΩ	-40.30V	-6.690nA	19.93mΩ
38	-43.61V	-7.010nA	19.84mΩ	-42.12V	-6.781nA	20.12mΩ
39	-41.32V	-6.709nA	19.46mΩ	-42.34V	-6.763nA	19.26mΩ
40	-40.10V	-6.846nA	20.18mΩ	-40.20V	-7.218nA	19.75mΩ
41	-40.30V	-7.503nA	20.21mΩ	-41.53V	-6.507nA	20.23mΩ
42	-40.92V	-6.618nA	19.89mΩ	-40.88V	-6.664nA	19.75mΩ
43	-40.29V	-6.713nA	19.59mΩ	-41.04V	-7.055nA	19.71mΩ
44	-43.34V	-6.856nA	19.93mΩ	-43.12V	-6.602nA	19.92mΩ
45	-39.51V	-7.408nA	20.20mΩ	-40.70V	-6.968nA	19.69mΩ
46	-39.82V	-6.593nA	19.66mΩ	-42.95V	-7.407nA	19.85mΩ
47	-43.55V	-7.227nA	19.73mΩ	-40.50V	-6.775nA	20.10mΩ
48	-41.71V	-6.892nA	19.65mΩ	-41.01V	-6.751nA	20.30mΩ
49	-41.43V	-7.593nA	19.33mΩ	-40.22V	-7.384nA	19.97mΩ
50	-43.05V	-7.558nA	19.91mΩ	-39.43V	-7.105nA	20.19mΩ
51	-39.93V	-6.507nA	19.96mΩ	-41.10V	-6.673nA	19.35mΩ
52	-41.77V	-6.515nA	19.58mΩ	-39.64V	-7.284nA	19.39mΩ
53	-42.30V	-6.594nA	20.04mΩ	-41.76V	-7.390nA	20.03mΩ
54	-41.56V	-7.465nA	19.42mΩ	-42.06V	-6.930nA	19.35mΩ
55	-41.19V	-7.362nA	19.49mΩ	-39.41V	-7.126nA	19.26mΩ
56	-41.44V	-6.781nA	20.38mΩ	-41.14V	-7.574nA	19.98mΩ
57	-39.85V	-6.987nA	19.85mΩ	-42.45V	-7.492nA	19.91mΩ
58	-40.35V	-7.417nA	20.13mΩ	-39.50V	-6.693nA	20.03mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 150℃, 1000Hrs
Test Date: 2021.07.13 ~ 2020.08.25
Test Standard : JESD22 STANDARD Method-A103
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-41.08V	-6.806nA	19.59mΩ	-43.57V	-7.437nA	19.80mΩ
60	-40.15V	-6.815nA	19.77mΩ	-42.85V	-6.831nA	19.43mΩ
61	-41.88V	-7.448nA	19.49mΩ	-41.59V	-6.596nA	19.59mΩ
62	-41.84V	-7.101nA	19.82mΩ	-40.04V	-7.397nA	20.33mΩ
63	-42.49V	-7.311nA	19.47mΩ	-39.48V	-7.393nA	20.21mΩ
64	-41.45V	-7.089nA	20.38mΩ	-41.48V	-7.000nA	20.11mΩ
65	-40.19V	-6.991nA	20.14mΩ	-41.99V	-7.174nA	19.57mΩ
66	-42.40V	-7.464nA	19.58mΩ	-39.59V	-7.219nA	19.65mΩ
67	-40.45V	-7.056nA	20.03mΩ	-39.58V	-6.656nA	19.31mΩ
68	-43.49V	-7.619nA	19.54mΩ	-39.81V	-6.587nA	19.70mΩ
69	-41.46V	-7.586nA	19.68mΩ	-41.87V	-7.477nA	19.64mΩ
70	-42.76V	-7.654nA	19.48mΩ	-41.57V	-7.167nA	20.32mΩ
71	-41.44V	-7.196nA	20.36mΩ	-42.96V	-7.401nA	20.38mΩ
72	-43.40V	-6.914nA	19.44mΩ	-43.27V	-7.514nA	19.62mΩ
73	-42.79V	-7.049nA	19.99mΩ	-43.22V	-7.401nA	19.67mΩ
74	-43.06V	-7.054nA	20.01mΩ	-40.54V	-7.090nA	19.47mΩ
75	-40.97V	-6.953nA	20.11mΩ	-42.56V	-6.822nA	20.18mΩ
76	-40.96V	-6.570nA	19.50mΩ	-43.22V	-7.467nA	19.63mΩ
77	-43.08V	-7.563nA	19.47mΩ	-43.57V	-6.625nA	19.76mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2021.07.12 ~ 2021.07.20
Test Standard : JESD22 STANDARD Method-A102
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-39.83V	-6.673nA	19.52mΩ	-40.31V	-7.114nA	19.38mΩ
2	-40.10V	-6.537nA	20.22mΩ	-42.22V	-7.391nA	19.68mΩ
3	-40.12V	-6.899nA	20.39mΩ	-42.59V	-6.837nA	19.54mΩ
4	-43.45V	-7.028nA	19.93mΩ	-40.64V	-7.042nA	20.26mΩ
5	-40.40V	-7.379nA	19.73mΩ	-42.36V	-6.519nA	20.39mΩ
6	-39.63V	-6.864nA	19.99mΩ	-40.89V	-7.334nA	19.60mΩ
7	-43.23V	-6.669nA	19.75mΩ	-40.08V	-7.384nA	19.72mΩ
8	-40.31V	-7.659nA	20.19mΩ	-42.61V	-7.234nA	19.77mΩ
9	-42.74V	-7.635nA	19.94mΩ	-40.66V	-6.559nA	19.47mΩ
10	-42.63V	-7.467nA	20.14mΩ	-41.73V	-6.746nA	19.95mΩ
11	-41.84V	-7.460nA	19.36mΩ	-43.03V	-6.956nA	19.38mΩ
12	-42.76V	-6.799nA	20.29mΩ	-42.50V	-7.535nA	19.59mΩ
13	-41.64V	-7.258nA	20.11mΩ	-39.48V	-6.830nA	19.51mΩ
14	-41.93V	-6.563nA	20.26mΩ	-40.48V	-7.368nA	19.43mΩ
15	-42.73V	-7.621nA	20.08mΩ	-39.52V	-7.626nA	19.67mΩ
16	-43.47V	-7.428nA	20.10mΩ	-39.86V	-7.628nA	19.75mΩ
17	-41.67V	-7.146nA	20.00mΩ	-42.07V	-6.569nA	20.13mΩ
18	-39.77V	-7.621nA	20.02mΩ	-41.66V	-7.335nA	19.34mΩ
19	-40.25V	-6.980nA	19.78mΩ	-41.16V	-7.298nA	19.32mΩ
20	-40.69V	-7.478nA	19.78mΩ	-40.19V	-7.317nA	20.27mΩ
21	-41.26V	-6.920nA	19.76mΩ	-40.29V	-6.640nA	19.94mΩ
22	-40.62V	-7.036nA	19.44mΩ	-43.20V	-7.322nA	19.61mΩ
23	-42.74V	-6.795nA	20.16mΩ	-39.53V	-7.240nA	19.32mΩ
24	-41.39V	-7.229nA	19.88mΩ	-42.41V	-7.267nA	19.70mΩ
25	-40.09V	-7.223nA	20.05mΩ	-39.59V	-7.363nA	20.19mΩ
26	-39.66V	-7.518nA	19.90mΩ	-39.49V	-7.439nA	19.32mΩ
27	-42.95V	-7.559nA	20.33mΩ	-41.09V	-6.945nA	19.27mΩ
28	-40.20V	-7.001nA	19.76mΩ	-41.98V	-7.334nA	19.53mΩ
29	-42.17V	-6.858nA	19.65mΩ	-39.53V	-7.344nA	20.35mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2021.07.12 ~ 2021.07.20
Test Standard : JESD22 STANDARD Method-A102
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-39.47V	-7.600nA	20.14mΩ	-42.92V	-7.458nA	19.50mΩ
31	-41.43V	-7.084nA	20.12mΩ	-39.89V	-6.884nA	20.17mΩ
32	-43.42V	-7.287nA	19.25mΩ	-39.95V	-6.928nA	20.33mΩ
33	-41.53V	-7.303nA	19.44mΩ	-43.35V	-7.024nA	19.72mΩ
34	-42.77V	-7.105nA	20.32mΩ	-40.01V	-7.146nA	19.56mΩ
35	-41.36V	-6.901nA	19.37mΩ	-41.27V	-7.030nA	20.33mΩ
36	-39.99V	-6.795nA	19.92mΩ	-39.56V	-7.502nA	19.53mΩ
37	-40.68V	-6.834nA	19.75mΩ	-42.28V	-6.628nA	19.87mΩ
38	-41.26V	-7.263nA	19.37mΩ	-41.77V	-6.781nA	19.49mΩ
39	-39.39V	-7.390nA	19.89mΩ	-42.76V	-7.558nA	19.52mΩ
40	-42.12V	-7.302nA	20.29mΩ	-41.52V	-6.803nA	19.83mΩ
41	-39.74V	-7.349nA	19.82mΩ	-41.06V	-6.858nA	19.32mΩ
42	-42.94V	-6.572nA	20.01mΩ	-41.20V	-6.978nA	20.30mΩ
43	-40.53V	-6.963nA	19.61mΩ	-42.66V	-7.367nA	19.91mΩ
44	-43.50V	-6.546nA	20.27mΩ	-42.58V	-6.502nA	20.32mΩ
45	-40.01V	-7.549nA	19.71mΩ	-42.38V	-7.352nA	20.13mΩ
46	-39.96V	-7.376nA	19.27mΩ	-42.80V	-7.618nA	19.89mΩ
47	-39.60V	-6.940nA	20.39mΩ	-41.06V	-6.942nA	20.29mΩ
48	-41.12V	-6.564nA	19.67mΩ	-42.91V	-6.548nA	20.22mΩ
49	-40.58V	-6.618nA	19.65mΩ	-39.72V	-6.521nA	20.05mΩ
50	-39.50V	-6.664nA	19.84mΩ	-42.97V	-7.553nA	19.48mΩ
51	-43.52V	-6.880nA	19.57mΩ	-42.16V	-6.859nA	19.32mΩ
52	-42.98V	-6.539nA	20.27mΩ	-43.18V	-7.215nA	19.43mΩ
53	-39.57V	-7.369nA	19.93mΩ	-40.09V	-7.450nA	19.46mΩ
54	-41.05V	-6.779nA	19.71mΩ	-41.52V	-7.291nA	20.13mΩ
55	-43.67V	-7.498nA	19.51mΩ	-42.20V	-6.748nA	19.76mΩ
56	-43.41V	-6.751nA	19.62mΩ	-40.84V	-7.478nA	20.20mΩ
57	-40.72V	-6.614nA	20.03mΩ	-41.76V	-7.010nA	19.83mΩ
58	-41.15V	-7.457nA	20.15mΩ	-42.83V	-6.593nA	20.36mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2021.07.12 ~ 2021.07.20
Test Standard : JESD22 STANDARD Method-A102
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-42.46V	-6.621nA	19.85mΩ	-39.54V	-7.392nA	19.66mΩ
60	-41.20V	-6.546nA	19.28mΩ	-40.01V	-7.477nA	19.34mΩ
61	-42.93V	-7.273nA	19.63mΩ	-41.01V	-7.381nA	19.33mΩ
62	-40.62V	-6.892nA	20.18mΩ	-41.62V	-7.440nA	20.07mΩ
63	-39.32V	-6.873nA	19.36mΩ	-41.66V	-7.404nA	20.30mΩ
64	-40.61V	-7.392nA	20.26mΩ	-40.77V	-6.601nA	19.60mΩ
65	-42.56V	-6.903nA	19.51mΩ	-40.30V	-7.148nA	19.35mΩ
66	-42.72V	-7.123nA	19.31mΩ	-42.43V	-7.580nA	19.40mΩ
67	-40.22V	-7.073nA	19.66mΩ	-41.12V	-6.771nA	20.36mΩ
68	-40.96V	-7.263nA	19.55mΩ	-40.62V	-6.557nA	19.71mΩ
69	-43.10V	-6.831nA	19.91mΩ	-40.65V	-7.548nA	20.02mΩ
70	-43.57V	-6.698nA	19.66mΩ	-39.91V	-6.570nA	20.09mΩ
71	-40.81V	-7.412nA	19.25mΩ	-42.61V	-7.330nA	19.98mΩ
72	-41.10V	-7.532nA	20.00mΩ	-39.59V	-7.147nA	19.73mΩ
73	-43.23V	-7.019nA	20.12mΩ	-40.21V	-6.974nA	19.31mΩ
74	-43.05V	-7.300nA	20.34mΩ	-43.02V	-7.337nA	20.30mΩ
75	-41.83V	-6.915nA	19.54mΩ	-43.45V	-7.618nA	19.45mΩ
76	-41.59V	-6.937nA	19.38mΩ	-43.00V	-6.603nA	19.55mΩ
77	-41.99V	-7.064nA	19.43mΩ	-42.59V	-6.671nA	19.45mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2021.07.20 ~ 2021.09.10
Test Standard : JESD22 STANDARD Method-A104
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-43.07V	-6.877nA	20.27mΩ	-40.50V	-7.463nA	19.61mΩ
2	-41.24V	-6.790nA	20.09mΩ	-42.02V	-7.651nA	20.27mΩ
3	-40.69V	-7.508nA	19.70mΩ	-41.28V	-6.884nA	19.82mΩ
4	-43.23V	-6.813nA	19.44mΩ	-41.41V	-6.732nA	20.40mΩ
5	-42.86V	-6.866nA	19.31mΩ	-43.05V	-6.663nA	19.37mΩ
6	-39.43V	-6.825nA	19.79mΩ	-43.02V	-7.259nA	20.19mΩ
7	-42.42V	-6.749nA	19.32mΩ	-42.94V	-7.199nA	19.76mΩ
8	-40.63V	-6.951nA	19.33mΩ	-39.30V	-6.568nA	20.00mΩ
9	-42.41V	-7.360nA	19.42mΩ	-39.47V	-7.334nA	19.55mΩ
10	-42.70V	-7.385nA	19.39mΩ	-41.82V	-7.359nA	19.50mΩ
11	-41.29V	-7.026nA	20.38mΩ	-40.91V	-7.371nA	19.33mΩ
12	-41.44V	-7.046nA	19.89mΩ	-42.30V	-6.927nA	20.09mΩ
13	-41.11V	-6.591nA	20.15mΩ	-42.63V	-7.079nA	20.21mΩ
14	-41.62V	-7.593nA	19.59mΩ	-40.77V	-7.384nA	20.11mΩ
15	-40.94V	-6.514nA	20.21mΩ	-42.38V	-6.787nA	20.02mΩ
16	-43.35V	-7.492nA	19.55mΩ	-43.73V	-6.900nA	20.25mΩ
17	-41.13V	-7.074nA	20.09mΩ	-40.85V	-7.551nA	19.44mΩ
18	-40.92V	-7.205nA	20.07mΩ	-41.29V	-7.121nA	19.54mΩ
19	-39.49V	-6.669nA	19.39mΩ	-39.82V	-7.487nA	19.45mΩ
20	-41.16V	-6.656nA	19.26mΩ	-41.34V	-7.276nA	19.92mΩ
21	-39.94V	-6.666nA	20.08mΩ	-42.06V	-7.193nA	19.75mΩ
22	-41.54V	-7.056nA	19.80mΩ	-42.90V	-7.320nA	19.83mΩ
23	-43.51V	-7.089nA	20.33mΩ	-43.57V	-7.502nA	19.39mΩ
24	-41.23V	-7.004nA	19.77mΩ	-43.71V	-6.511nA	19.73mΩ
25	-40.94V	-6.892nA	19.59mΩ	-42.52V	-7.140nA	19.34mΩ
26	-43.29V	-6.573nA	19.98mΩ	-41.99V	-7.486nA	19.81mΩ
27	-42.06V	-6.916nA	19.88mΩ	-39.46V	-6.947nA	20.02mΩ
28	-43.59V	-6.872nA	19.76mΩ	-43.66V	-7.646nA	19.70mΩ
29	-39.74V	-6.538nA	20.02mΩ	-43.02V	-6.526nA	19.80mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2021.07.20 ~ 2021.09.10
Test Standard : JESD22 STANDARD Method-A104
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-40.28V	-6.590nA	19.83mΩ	-40.95V	-6.841nA	19.60mΩ
31	-42.13V	-7.602nA	20.07mΩ	-40.37V	-6.926nA	20.01mΩ
32	-41.13V	-6.893nA	19.87mΩ	-39.55V	-6.795nA	19.76mΩ
33	-41.73V	-7.490nA	20.13mΩ	-40.65V	-7.223nA	19.52mΩ
34	-39.93V	-7.552nA	20.13mΩ	-39.77V	-7.144nA	19.56mΩ
35	-41.49V	-6.558nA	19.81mΩ	-41.99V	-6.998nA	20.28mΩ
36	-41.09V	-6.925nA	20.02mΩ	-40.18V	-7.120nA	20.07mΩ
37	-42.77V	-6.970nA	19.46mΩ	-39.35V	-6.812nA	20.07mΩ
38	-40.98V	-6.736nA	19.59mΩ	-42.63V	-7.087nA	20.23mΩ
39	-39.33V	-6.603nA	19.72mΩ	-43.24V	-7.469nA	19.25mΩ
40	-42.25V	-7.284nA	19.54mΩ	-40.50V	-6.665nA	19.77mΩ
41	-39.39V	-6.907nA	19.94mΩ	-40.90V	-6.567nA	19.59mΩ
42	-39.71V	-7.094nA	20.14mΩ	-41.26V	-6.537nA	20.31mΩ
43	-42.24V	-7.121nA	19.52mΩ	-41.34V	-7.114nA	19.70mΩ
44	-42.58V	-6.825nA	19.96mΩ	-42.22V	-6.914nA	19.70mΩ
45	-39.45V	-6.932nA	19.40mΩ	-39.73V	-6.564nA	20.33mΩ
46	-42.99V	-7.064nA	20.08mΩ	-41.78V	-6.685nA	20.13mΩ
47	-39.62V	-7.225nA	20.07mΩ	-39.72V	-6.884nA	19.54mΩ
48	-41.96V	-7.555nA	19.45mΩ	-42.74V	-6.848nA	19.52mΩ
49	-43.64V	-6.726nA	19.27mΩ	-42.96V	-7.440nA	20.18mΩ
50	-42.23V	-7.257nA	20.19mΩ	-43.21V	-7.650nA	19.27mΩ
51	-40.56V	-7.172nA	20.23mΩ	-41.45V	-7.658nA	20.24mΩ
52	-42.26V	-7.212nA	20.09mΩ	-43.69V	-6.777nA	20.11mΩ
53	-40.88V	-7.401nA	19.67mΩ	-39.41V	-6.595nA	20.37mΩ
54	-41.34V	-7.036nA	20.15mΩ	-42.71V	-6.725nA	20.07mΩ
55	-41.97V	-6.718nA	19.65mΩ	-40.85V	-7.403nA	20.02mΩ
56	-40.81V	-7.239nA	19.47mΩ	-39.29V	-6.654nA	19.26mΩ
57	-40.26V	-7.528nA	19.79mΩ	-42.48V	-7.240nA	19.58mΩ
58	-39.57V	-7.410nA	20.29mΩ	-43.17V	-7.179nA	19.82mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2021.07.20 ~ 2021.09.10
Test Standard : JESD22 STANDARD Method-A104
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-43.72V	-7.563nA	19.44mΩ	-42.55V	-7.327nA	20.25mΩ
60	-40.54V	-6.572nA	19.60mΩ	-43.06V	-6.911nA	19.38mΩ
61	-40.44V	-7.625nA	20.17mΩ	-39.64V	-7.364nA	20.16mΩ
62	-40.24V	-6.719nA	19.77mΩ	-43.63V	-7.174nA	19.50mΩ
63	-40.62V	-6.972nA	19.77mΩ	-40.32V	-7.136nA	20.32mΩ
64	-42.48V	-7.461nA	19.69mΩ	-42.65V	-7.215nA	19.87mΩ
65	-42.18V	-6.968nA	19.98mΩ	-41.89V	-7.248nA	19.76mΩ
66	-39.91V	-7.501nA	19.97mΩ	-43.10V	-6.995nA	19.90mΩ
67	-43.09V	-7.623nA	19.55mΩ	-41.10V	-7.016nA	19.39mΩ
68	-39.99V	-7.072nA	19.29mΩ	-42.69V	-7.509nA	19.43mΩ
69	-41.77V	-7.376nA	19.86mΩ	-42.45V	-7.290nA	19.61mΩ
70	-42.03V	-6.945nA	19.72mΩ	-41.48V	-6.956nA	19.59mΩ
71	-40.35V	-7.255nA	19.50mΩ	-41.23V	-7.322nA	19.88mΩ
72	-39.89V	-6.582nA	19.93mΩ	-41.49V	-7.594nA	19.90mΩ
73	-42.68V	-6.891nA	20.30mΩ	-41.35V	-6.724nA	20.20mΩ
74	-42.85V	-7.359nA	19.32mΩ	-42.80V	-7.048nA	19.60mΩ
75	-41.04V	-7.090nA	19.88mΩ	-39.43V	-6.807nA	19.26mΩ
76	-41.67V	-6.654nA	19.41mΩ	-42.02V	-7.132nA	19.36mΩ
77	-43.33V	-6.819nA	20.30mΩ	-39.45V	-7.611nA	19.59mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2021.07.20 ~ 2021.09.01
Test Standard : JESD22 STANDARD Method-A101
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-41.50V	-7.287nA	19.91mΩ	-41.43V	-6.935nA	20.05mΩ
2	-40.53V	-7.162nA	19.38mΩ	-41.92V	-7.018nA	19.55mΩ
3	-43.66V	-7.482nA	19.62mΩ	-42.81V	-7.195nA	19.57mΩ
4	-41.69V	-7.237nA	19.79mΩ	-40.86V	-6.868nA	19.64mΩ
5	-43.11V	-7.369nA	20.21mΩ	-41.94V	-7.180nA	19.98mΩ
6	-42.86V	-7.517nA	19.85mΩ	-42.29V	-6.976nA	20.33mΩ
7	-42.24V	-7.563nA	19.26mΩ	-39.84V	-6.984nA	19.89mΩ
8	-41.99V	-6.944nA	19.96mΩ	-42.88V	-7.371nA	19.74mΩ
9	-42.09V	-7.532nA	20.02mΩ	-40.62V	-6.920nA	19.37mΩ
10	-42.82V	-6.741nA	19.58mΩ	-40.15V	-6.539nA	19.97mΩ
11	-43.38V	-7.317nA	19.62mΩ	-40.84V	-7.029nA	19.65mΩ
12	-39.51V	-7.269nA	19.62mΩ	-39.73V	-6.570nA	19.71mΩ
13	-42.62V	-7.142nA	19.43mΩ	-41.81V	-6.919nA	19.92mΩ
14	-41.44V	-7.103nA	20.28mΩ	-40.11V	-7.309nA	20.25mΩ
15	-42.45V	-7.399nA	19.98mΩ	-41.42V	-6.979nA	19.88mΩ
16	-41.86V	-7.090nA	19.52mΩ	-40.89V	-7.463nA	20.28mΩ
17	-42.96V	-6.801nA	20.00mΩ	-41.15V	-7.181nA	20.33mΩ
18	-41.44V	-6.910nA	19.30mΩ	-43.69V	-6.815nA	19.94mΩ
19	-41.70V	-7.599nA	19.44mΩ	-39.83V	-6.633nA	19.67mΩ
20	-39.91V	-7.416nA	19.57mΩ	-41.44V	-7.605nA	19.67mΩ
21	-40.27V	-6.656nA	20.11mΩ	-43.48V	-7.289nA	19.66mΩ
22	-40.52V	-6.839nA	19.49mΩ	-43.53V	-7.308nA	19.66mΩ
23	-43.24V	-6.791nA	20.39mΩ	-40.05V	-7.372nA	19.97mΩ
24	-43.40V	-7.653nA	19.95mΩ	-43.68V	-6.763nA	19.26mΩ
25	-42.43V	-7.159nA	19.63mΩ	-42.94V	-7.021nA	19.77mΩ
26	-41.32V	-7.535nA	19.82mΩ	-42.90V	-7.123nA	19.84mΩ
27	-39.62V	-7.237nA	20.13mΩ	-41.35V	-6.702nA	20.28mΩ
28	-43.54V	-7.625nA	19.76mΩ	-41.72V	-6.587nA	19.45mΩ
29	-42.67V	-6.707nA	20.14mΩ	-43.00V	-7.536nA	20.14mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2021.07.20 ~ 2021.09.01
Test Standard : JESD22 STANDARD Method-A101
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-40.67V	-6.781nA	20.33mΩ	-41.67V	-7.650nA	19.74mΩ
31	-41.80V	-6.571nA	19.54mΩ	-40.15V	-6.786nA	19.36mΩ
32	-42.39V	-7.416nA	20.35mΩ	-42.19V	-6.948nA	20.12mΩ
33	-40.87V	-6.878nA	19.76mΩ	-41.21V	-7.000nA	19.89mΩ
34	-40.81V	-7.620nA	19.65mΩ	-42.68V	-6.750nA	19.63mΩ
35	-40.36V	-7.102nA	19.86mΩ	-41.72V	-7.184nA	19.57mΩ
36	-41.47V	-7.096nA	20.15mΩ	-40.86V	-6.848nA	20.39mΩ
37	-41.64V	-7.415nA	19.99mΩ	-42.54V	-7.528nA	19.56mΩ
38	-40.61V	-6.593nA	20.23mΩ	-43.02V	-6.988nA	19.36mΩ
39	-40.85V	-7.118nA	20.29mΩ	-41.94V	-7.596nA	19.77mΩ
40	-42.03V	-6.758nA	19.68mΩ	-39.78V	-7.449nA	19.29mΩ
41	-40.61V	-7.133nA	19.68mΩ	-40.79V	-7.468nA	19.65mΩ
42	-40.46V	-7.526nA	19.56mΩ	-43.36V	-7.399nA	19.32mΩ
43	-39.69V	-7.237nA	19.46mΩ	-41.32V	-7.423nA	19.92mΩ
44	-43.03V	-6.679nA	19.25mΩ	-40.14V	-6.944nA	19.31mΩ
45	-43.70V	-7.323nA	19.72mΩ	-39.74V	-7.507nA	19.89mΩ
46	-39.42V	-6.582nA	19.72mΩ	-43.30V	-6.958nA	19.56mΩ
47	-42.50V	-7.065nA	19.53mΩ	-40.61V	-7.648nA	20.14mΩ
48	-41.62V	-6.630nA	19.71mΩ	-41.15V	-6.512nA	19.43mΩ
49	-42.56V	-7.009nA	19.32mΩ	-40.75V	-6.582nA	19.34mΩ
50	-41.90V	-6.648nA	19.48mΩ	-43.18V	-6.521nA	19.30mΩ
51	-40.02V	-6.938nA	19.45mΩ	-40.96V	-7.099nA	19.90mΩ
52	-39.55V	-7.030nA	19.63mΩ	-41.17V	-7.127nA	20.32mΩ
53	-43.73V	-6.957nA	19.30mΩ	-42.97V	-6.964nA	20.32mΩ
54	-40.49V	-7.647nA	19.39mΩ	-41.60V	-6.726nA	19.62mΩ
55	-41.06V	-7.402nA	19.53mΩ	-43.21V	-6.500nA	19.79mΩ
56	-39.59V	-7.132nA	19.73mΩ	-41.43V	-6.629nA	19.67mΩ
57	-42.50V	-7.474nA	19.88mΩ	-40.06V	-7.248nA	20.29mΩ
58	-39.80V	-7.057nA	20.23mΩ	-42.17V	-6.744nA	19.26mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2021.07.20 ~ 2021.09.01
Test Standard : JESD22 STANDARD Method-A101
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-40.27V	-7.611nA	19.96mΩ	-42.55V	-7.140nA	19.93mΩ
60	-41.40V	-7.258nA	20.05mΩ	-41.64V	-6.883nA	20.33mΩ
61	-42.14V	-7.473nA	19.75mΩ	-39.36V	-6.605nA	20.21mΩ
62	-41.72V	-7.542nA	19.50mΩ	-40.51V	-6.913nA	20.34mΩ
63	-43.14V	-7.609nA	19.45mΩ	-40.47V	-6.781nA	20.26mΩ
64	-43.10V	-6.569nA	20.15mΩ	-41.76V	-7.375nA	19.27mΩ
65	-39.63V	-7.010nA	19.62mΩ	-43.35V	-7.367nA	19.40mΩ
66	-43.57V	-7.609nA	19.61mΩ	-40.14V	-7.535nA	19.37mΩ
67	-43.18V	-7.422nA	20.33mΩ	-39.33V	-6.849nA	19.38mΩ
68	-42.51V	-7.277nA	20.27mΩ	-41.16V	-7.365nA	19.78mΩ
69	-41.14V	-7.333nA	19.63mΩ	-42.82V	-7.160nA	19.76mΩ
70	-39.66V	-6.995nA	19.42mΩ	-42.48V	-6.689nA	19.35mΩ
71	-40.63V	-6.660nA	19.57mΩ	-41.78V	-7.321nA	20.40mΩ
72	-42.90V	-7.235nA	19.46mΩ	-40.80V	-6.613nA	20.39mΩ
73	-43.29V	-7.262nA	19.63mΩ	-42.96V	-6.755nA	20.17mΩ
74	-40.88V	-7.183nA	19.48mΩ	-43.47V	-7.150nA	19.68mΩ
75	-43.70V	-6.731nA	19.27mΩ	-39.69V	-7.247nA	19.54mΩ
76	-41.34V	-7.589nA	20.28mΩ	-40.38V	-6.950nA	20.05mΩ
77	-42.70V	-6.705nA	20.15mΩ	-40.52V	-7.023nA	20.23mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2021.07.20 ~ 2021.09.01
Test Standard : JESD22 STANDARD Method-A101
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-39.61V	-7.108nA	20.40mΩ	-40.52V	-6.741nA	19.95mΩ
2	-43.14V	-6.794nA	19.33mΩ	-40.29V	-7.031nA	20.18mΩ
3	-40.53V	-7.599nA	19.80mΩ	-41.61V	-7.016nA	19.50mΩ
4	-43.01V	-7.473nA	20.10mΩ	-42.50V	-6.896nA	19.33mΩ
5	-43.52V	-6.848nA	19.89mΩ	-43.61V	-7.570nA	19.54mΩ
6	-39.34V	-6.639nA	19.48mΩ	-42.86V	-6.665nA	19.83mΩ
7	-41.82V	-6.813nA	19.60mΩ	-42.16V	-7.025nA	20.15mΩ
8	-43.21V	-7.346nA	19.88mΩ	-43.59V	-6.929nA	20.06mΩ
9	-40.66V	-7.636nA	19.82mΩ	-41.23V	-6.532nA	20.31mΩ
10	-42.92V	-6.689nA	20.19mΩ	-40.16V	-7.358nA	19.54mΩ
11	-39.64V	-6.545nA	20.14mΩ	-43.61V	-6.779nA	19.36mΩ
12	-39.60V	-7.158nA	20.15mΩ	-40.44V	-7.243nA	19.27mΩ
13	-41.23V	-7.001nA	20.15mΩ	-42.96V	-7.296nA	20.07mΩ
14	-40.54V	-6.821nA	20.06mΩ	-39.68V	-6.596nA	19.68mΩ
15	-41.90V	-6.909nA	19.83mΩ	-39.72V	-7.276nA	20.07mΩ
16	-40.24V	-7.372nA	19.50mΩ	-39.63V	-6.595nA	19.66mΩ
17	-41.20V	-6.635nA	20.17mΩ	-42.21V	-6.787nA	20.20mΩ
18	-43.58V	-7.032nA	19.81mΩ	-40.23V	-6.633nA	19.69mΩ
19	-41.51V	-7.374nA	19.34mΩ	-40.67V	-7.535nA	19.43mΩ
20	-42.01V	-6.949nA	19.39mΩ	-42.94V	-7.378nA	19.67mΩ
21	-43.68V	-6.604nA	19.37mΩ	-40.88V	-6.904nA	20.05mΩ
22	-40.13V	-6.591nA	19.99mΩ	-41.06V	-7.305nA	19.75mΩ
23	-40.46V	-7.393nA	19.69mΩ	-41.51V	-6.561nA	19.46mΩ
24	-41.84V	-7.127nA	19.30mΩ	-42.33V	-6.933nA	20.04mΩ
25	-42.21V	-7.115nA	19.32mΩ	-39.30V	-6.878nA	19.76mΩ
26	-40.98V	-6.846nA	19.46mΩ	-40.68V	-6.832nA	19.66mΩ
27	-42.78V	-7.214nA	20.26mΩ	-39.45V	-7.412nA	19.32mΩ
28	-42.17V	-7.316nA	19.55mΩ	-40.47V	-6.716nA	19.82mΩ
29	-40.12V	-6.826nA	19.54mΩ	-43.07V	-6.675nA	19.59mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2021.07.20 ~ 2021.09.01
Test Standard : JESD22 STANDARD Method-A101
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	-42.69V	-7.390nA	20.20mΩ	-39.61V	-6.999nA	19.99mΩ
31	-42.20V	-7.395nA	20.34mΩ	-40.99V	-7.584nA	20.15mΩ
32	-39.70V	-7.028nA	19.63mΩ	-41.10V	-7.117nA	19.83mΩ
33	-39.40V	-7.184nA	19.28mΩ	-40.33V	-7.104nA	20.21mΩ
34	-42.00V	-7.275nA	19.31mΩ	-42.91V	-7.617nA	19.66mΩ
35	-40.24V	-6.987nA	20.18mΩ	-40.42V	-6.506nA	19.94mΩ
36	-40.94V	-6.923nA	19.99mΩ	-42.82V	-7.375nA	19.25mΩ
37	-40.32V	-6.679nA	19.32mΩ	-40.60V	-7.388nA	19.31mΩ
38	-39.93V	-6.666nA	20.11mΩ	-42.84V	-7.339nA	20.12mΩ
39	-42.60V	-6.657nA	19.52mΩ	-43.41V	-7.576nA	20.30mΩ
40	-43.43V	-7.171nA	20.02mΩ	-43.33V	-7.134nA	19.90mΩ
41	-43.13V	-6.737nA	19.69mΩ	-43.02V	-7.016nA	20.09mΩ
42	-43.37V	-7.530nA	19.49mΩ	-42.65V	-6.855nA	19.82mΩ
43	-41.81V	-7.361nA	19.83mΩ	-43.59V	-7.449nA	19.54mΩ
44	-41.18V	-6.908nA	19.35mΩ	-41.83V	-7.630nA	20.04mΩ
45	-40.09V	-6.499nA	19.41mΩ	-41.63V	-7.305nA	19.25mΩ
46	-42.53V	-6.880nA	19.34mΩ	-39.64V	-7.185nA	19.84mΩ
47	-39.41V	-7.186nA	19.39mΩ	-42.21V	-6.627nA	19.76mΩ
48	-41.67V	-6.743nA	19.66mΩ	-43.73V	-7.208nA	19.84mΩ
49	-42.97V	-7.460nA	19.49mΩ	-40.61V	-7.651nA	19.87mΩ
50	-42.03V	-7.582nA	19.34mΩ	-40.99V	-7.462nA	19.96mΩ
51	-42.48V	-7.076nA	19.64mΩ	-41.66V	-7.161nA	19.75mΩ
52	-39.30V	-6.749nA	19.28mΩ	-40.90V	-7.651nA	19.57mΩ
53	-40.17V	-6.759nA	19.27mΩ	-39.71V	-7.166nA	19.32mΩ
54	-40.66V	-7.370nA	19.55mΩ	-43.45V	-6.661nA	19.73mΩ
55	-39.65V	-7.099nA	19.51mΩ	-40.66V	-7.480nA	19.33mΩ
56	-39.63V	-7.021nA	19.95mΩ	-39.39V	-7.192nA	19.99mΩ
57	-39.67V	-7.505nA	20.32mΩ	-39.69V	-6.706nA	19.76mΩ
58	-39.69V	-7.503nA	20.30mΩ	-41.16V	-6.972nA	20.18mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2021.07.20 ~ 2021.09.01
Test Standard : JESD22 STANDARD Method-A101
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	-39.74V	-7.215nA	19.93mΩ	-41.08V	-6.718nA	20.35mΩ
60	-42.89V	-6.794nA	20.23mΩ	-41.34V	-7.604nA	19.34mΩ
61	-43.13V	-7.639nA	20.19mΩ	-42.08V	-7.299nA	20.06mΩ
62	-39.92V	-6.598nA	19.25mΩ	-42.38V	-7.306nA	19.65mΩ
63	-41.33V	-7.187nA	20.24mΩ	-41.97V	-7.202nA	19.41mΩ
64	-43.20V	-6.893nA	20.36mΩ	-40.06V	-7.306nA	19.71mΩ
65	-40.31V	-7.226nA	20.24mΩ	-43.62V	-6.852nA	20.31mΩ
66	-43.68V	-7.544nA	19.50mΩ	-43.05V	-6.938nA	20.04mΩ
67	-40.51V	-6.789nA	20.06mΩ	-42.08V	-6.632nA	20.24mΩ
68	-39.95V	-6.615nA	20.09mΩ	-42.65V	-7.555nA	19.78mΩ
69	-39.53V	-7.313nA	20.16mΩ	-42.28V	-7.007nA	20.29mΩ
70	-43.51V	-7.613nA	19.29mΩ	-39.75V	-6.741nA	20.37mΩ
71	-39.51V	-6.563nA	20.09mΩ	-41.11V	-7.162nA	19.29mΩ
72	-43.67V	-7.234nA	19.47mΩ	-41.56V	-7.108nA	20.02mΩ
73	-39.68V	-7.519nA	19.32mΩ	-41.82V	-6.552nA	19.80mΩ
74	-42.09V	-6.731nA	19.63mΩ	-41.30V	-7.424nA	20.36mΩ
75	-42.18V	-7.595nA	20.01mΩ	-39.76V	-6.995nA	19.78mΩ
76	-42.21V	-7.447nA	20.28mΩ	-39.88V	-7.538nA	19.92mΩ
77	-41.39V	-6.799nA	19.53mΩ	-39.35V	-7.307nA	19.77mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Solderability Test Data

Report No : T210910-SG4835P
Part No : SSG4835P-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : -30V <V(BR)DSS @ID=-250μA ；IDSS < -1.0μA@VDS=-24V
RDS(ON) < 21mΩ@VGS=-10V, ID=-7.6A
Test Condition: 245℃ ± 5℃, 5Sec
Test Date: 2021.09.10
Test Standard : JESD22 STANDER Method-B102
Operator: Joe Lee

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	-43.10V	-6.958nA	19.56mΩ	-41.03V	-7.132nA	20.06mΩ
2	-43.73V	-7.631nA	19.73mΩ	-42.13V	-7.492nA	19.86mΩ
3	-41.41V	-6.527nA	20.04mΩ	-40.14V	-7.272nA	19.96mΩ
4	-40.40V	-6.511nA	20.03mΩ	-41.14V	-6.628nA	19.73mΩ
5	-43.72V	-7.268nA	20.27mΩ	-41.21V	-6.764nA	19.50mΩ
6	-41.40V	-7.605nA	20.37mΩ	-39.87V	-7.446nA	19.85mΩ
7	-39.64V	-6.833nA	19.91mΩ	-42.82V	-6.856nA	20.38mΩ
8	-41.32V	-7.085nA	20.02mΩ	-41.61V	-6.547nA	19.48mΩ
9	-39.69V	-7.153nA	19.65mΩ	-39.89V	-7.453nA	20.06mΩ
10	-40.03V	-6.582nA	19.73mΩ	-39.48V	-7.659nA	20.10mΩ

Made By: King Huang

Approval: Peter Yang